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OFFICIAL

PATENT  
81790.0189

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of:

MOMOHARA, Tomomi

Serial No: 09/686,200 (reissue of U.S. Patent  
No. 5,818,249)

Filed: October 5, 2000

For: PROBE CARD HAVING GROUPS  
OF PROBE NEEDLES IN A  
PROBING TEST APPARATUS FOR  
TESTING SEMICONDUCTOR  
INTEGRATED CIRCUITS

Art Unit: 2829

Examiner: NGUYEN, Vinh P.

I hereby certify that this correspondence is being  
facsimile transmitted to the United States Patent  
and Trademark Office at (703) 872-9306, on:

December 24, 2003

Date of Deposit

Michael Crapenchoff, Reg. No. 37,115

Name

*Michael Crapenchoff*

December 24, 2003

Signature

Date

SUPPLEMENTARY AMENDMENT

Commissioner for Patents  
Washington, D.C. 20231

Dear Sir:

In response to the Office's Communication dated June 25, 2003, the time for response to which is extended five months by the accompanying petition from July 25, 2003 to December 25, 2003, please amend the above-referenced reissue application as follows: